1 Features

- Protection Against 1-kV, 42-Ω IEC 61000-4-5 Surge Test for Industrial Signal Lines
- Bidirectional Polarity Enables Protection Against Bipolar Signaling or Miswiring Conditions
- Clamping Voltage of 34 V at 27-A, 8/20-µs Surge Current
- Standoff Voltage: ±27 V
- Small 3 mm × 3 mm² SON Footprint
- Survives Over 5,000 Repetitive Strikes of 27-A 8/20-µs Surge Current at 125°C
- Robust Surge Protection
  - IEC61000-4-5 (8/20 µs): 27 A
  - IEC61643-321 (10/1000 µs): 3.5 A
- Low Leakage Current
  - 0.8-nA Typical at 27°C
  - 400-nA Maximum at 85°C
- Low Capacitance: 57 pF
- Integrated Level 4 IEC 61000-4-2 ESD Protection

2 Applications

- Industrial Sensor I/O
- PLC I/O Modules
- Analog Inputs
- Appliances
- Medical Equipment
- Building Automation

3 Description

The TVS2701 device shunts up to 27 A of IEC 61000-4-5 fault current to protect systems from high-power transients or lightning strikes. The device survives the common industrial signal line EMC requirement of 1-kV IEC 61000-4-5 open circuit voltage coupled through a 42-Ω impedance. The TVS2701 uses a feedback mechanism to ensure precise flat clamping during a fault, keeping system exposure lower than traditional TVS diodes. The tight voltage regulation allows designers to confidently select system components with a lower voltage tolerance, lowering system costs and complexity without sacrificing robustness. The TVS2701 has a ±27-V operating range to enable operation in systems that require protection against reverse wiring conditions.

In addition, the TVS2701 is available in a small SON footprint designed for space-constrained applications, offering a significant size reduction compared to standard SMA and SMB packages. Low device leakage and capacitance ensure a minimal effect on the protected line. To ensure robust protection over the lifetime of the product, TI tests the TVS2701 against 5000 repetitive surge strikes at 125°C with no shift in device performance.

The TVS2701 is part of TI’s Flat-Clamp family of surge devices. For a deeper look at the Flat-Clamp family, refer to the Flat-Clamp Surge Protection Technology for Efficient System Protection white paper.

Device Information(1)

<table>
<thead>
<tr>
<th>PART NUMBER</th>
<th>PACKAGE</th>
<th>BODY SIZE (NOM)</th>
</tr>
</thead>
<tbody>
<tr>
<td>TVS2701</td>
<td>SON (8)</td>
<td>3.00 mm x 3.00 mm</td>
</tr>
</tbody>
</table>

(1) For all available packages, see the orderable addendum at the end of the data sheet.

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An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.
4 Revision History

Changes from Original (September 2018) to Revision A

- Changed from Advance Information to Production Data .............................................................. 1
## 5 Device Comparison Table

<table>
<thead>
<tr>
<th>DEVICE</th>
<th>V(_{\text{rwm}})</th>
<th>V(<em>{\text{clamp}}) at I(</em>{\text{PP}})</th>
<th>I(_{\text{PP}}) (8/20 µs)</th>
<th>Leakage at V(_{\text{rwm}})</th>
<th>POLARITY</th>
<th>Package</th>
</tr>
</thead>
<tbody>
<tr>
<td>TVS0500</td>
<td>5</td>
<td>9.2 V</td>
<td>43 A</td>
<td>0.07 nA</td>
<td>Unidirectional</td>
<td>DRV (SON-6)</td>
</tr>
<tr>
<td>TVS0701</td>
<td>7</td>
<td>11 V</td>
<td>30 A</td>
<td>0.25 nA</td>
<td>Bidirectional</td>
<td>DRB (SON-8)</td>
</tr>
<tr>
<td>TVS1400</td>
<td>14</td>
<td>18.6 V</td>
<td>43 A</td>
<td>2 nA</td>
<td>Unidirectional</td>
<td>DRV (SON-6)</td>
</tr>
<tr>
<td>TVS1401</td>
<td>14</td>
<td>20.5 V</td>
<td>30 A</td>
<td>1.1 nA</td>
<td>Bidirectional</td>
<td>DRB (SON-8)</td>
</tr>
<tr>
<td>TVS1800</td>
<td>18</td>
<td>22.8 V</td>
<td>40 A</td>
<td>0.3 nA</td>
<td>Unidirectional</td>
<td>DRV (SON-6)</td>
</tr>
<tr>
<td>TVS1801</td>
<td>18</td>
<td>27.4 V</td>
<td>30 A</td>
<td>0.4 nA</td>
<td>Bidirectional</td>
<td>DRB (SON-8)</td>
</tr>
<tr>
<td>TVS2200</td>
<td>22</td>
<td>27.7 V</td>
<td>40 A</td>
<td>3.2 nA</td>
<td>Unidirectional</td>
<td>DRV (SON-6)</td>
</tr>
<tr>
<td>TVS2201</td>
<td>22</td>
<td>29.6 V</td>
<td>30 A</td>
<td>2 nA</td>
<td>Bidirectional</td>
<td>DRB (SON-8)</td>
</tr>
<tr>
<td>TVS2700</td>
<td>27</td>
<td>32.5 V</td>
<td>40 A</td>
<td>1.7 nA</td>
<td>Unidirectional</td>
<td>DRV (SON-6)</td>
</tr>
<tr>
<td>TVS2701</td>
<td>27</td>
<td>34 V</td>
<td>27 A</td>
<td>0.8 nA</td>
<td>Bidirectional</td>
<td>DRB (SON-8)</td>
</tr>
<tr>
<td>TVS3300</td>
<td>33</td>
<td>38 V</td>
<td>35 A</td>
<td>19 nA</td>
<td>Unidirectional</td>
<td>DRV (SON-6), YZF (WCSP)</td>
</tr>
<tr>
<td>TVS3301</td>
<td>33</td>
<td>40 V</td>
<td>27 A</td>
<td>2.5 nA</td>
<td>Bidirectional</td>
<td>DRB (SON-8)</td>
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</table>
6 Pin Configuration and Functions

Pin Functions

<table>
<thead>
<tr>
<th>PIN</th>
<th>DRB</th>
<th>TYPE</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>NAME</td>
<td>DRB</td>
<td>TYPE</td>
<td>DESCRIPTION</td>
</tr>
<tr>
<td>IN</td>
<td>1, 2, 3, 4</td>
<td>IN</td>
<td>Surge Protected Channel</td>
</tr>
<tr>
<td>GND</td>
<td>5, 6, 7, 8</td>
<td>GND</td>
<td>Ground</td>
</tr>
<tr>
<td>FLOAT</td>
<td>Exposed Thermal Pad</td>
<td>NC</td>
<td>Exposed Thermal Pad Must Be Floating</td>
</tr>
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</table>

Not to scale
7 Specifications

7.1 Absolute Maximum Ratings

\( T_A = 27°C \) (unless otherwise noted)\(^{(1)} \)

<table>
<thead>
<tr>
<th>Maximum Surge</th>
<th>MIN</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>IEC 61000-4-5 Current (8/20 ( \mu )s), ( T_A &lt; 125°C )</td>
<td>±27</td>
<td>A</td>
<td></td>
</tr>
<tr>
<td>IEC 61000-4-5 Power (8/20 ( \mu )s)</td>
<td>950</td>
<td>W</td>
<td></td>
</tr>
<tr>
<td>IEC 61643-321 Current (10/1000 ( \mu )s)</td>
<td>±3.5</td>
<td>A</td>
<td></td>
</tr>
<tr>
<td>IEC 61643-321 Power (10/1000 ( \mu )s)</td>
<td>120</td>
<td>W</td>
<td></td>
</tr>
</tbody>
</table>

| EFT | IEC 61000-4-4 EFT Protection | ±80 | A |
| I\( \text{gr} \) | DC Current | 25 | mA |
| \( T_A \) | Ambient Operating Temperature | -40 | 125 | °C |
| \( T_{\text{stg}} \) | Storage Temperature | -65 | 150 | °C |

\(^{(1)}\) Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 ESD Ratings - JEDEC

<table>
<thead>
<tr>
<th>( V_{(ESD)} )</th>
<th>Electrostatic discharge</th>
<th>VALUE</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins(^{(1)} )</td>
<td>±2000</td>
<td>V</td>
<td></td>
</tr>
<tr>
<td>Charged device model (CDM), per JEDEC specification/JESD22-C101, all pins(^{(2)} )</td>
<td>±500</td>
<td>V</td>
<td></td>
</tr>
</tbody>
</table>

\(^{(1)}\) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

\(^{(2)}\) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

7.3 ESD Ratings - IEC

<table>
<thead>
<tr>
<th>( V_{(ESD)} )</th>
<th>Electrostatic discharge</th>
<th>VALUE</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>IEC 61000-4-2 contact discharge</td>
<td>±8</td>
<td>kV</td>
<td></td>
</tr>
<tr>
<td>IEC 61000-4-2 air-gap discharge</td>
<td>±15</td>
<td>kV</td>
<td></td>
</tr>
</tbody>
</table>

7.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

<table>
<thead>
<tr>
<th>( V_{RWM} )</th>
<th>Reverse Stand-Off Voltage</th>
<th>MIN</th>
<th>NOM</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>±27</td>
<td>V</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

7.5 Thermal Information

<table>
<thead>
<tr>
<th>THERMAL METRIC(^{(1)} )</th>
<th>( \text{TVS2701} )</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>( R_{\text{qJA}} )</td>
<td>Junction-to-ambient thermal resistance</td>
<td>52</td>
</tr>
<tr>
<td>( R_{\text{qJC(top)}} )</td>
<td>Junction-to-case (top) thermal resistance</td>
<td>56.1</td>
</tr>
<tr>
<td>( R_{\text{JB}} )</td>
<td>Junction-to-board thermal resistance</td>
<td>24.9</td>
</tr>
<tr>
<td>( Y_{\text{JT}} )</td>
<td>Junction-to-top characterization parameter</td>
<td>2.1</td>
</tr>
<tr>
<td>( Y_{\text{JB}} )</td>
<td>Junction-to-board characterization parameter</td>
<td>24.8</td>
</tr>
<tr>
<td>( R_{\text{qJC(bot)}} )</td>
<td>Junction-to-case (bottom) thermal resistance</td>
<td>9.8</td>
</tr>
</tbody>
</table>

\(^{(1)}\) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.
## 7.6 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>TEST CONDITIONS</th>
<th>MIN</th>
<th>TYP</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>I(_{\text{LEAK}})</td>
<td>Leakage Current</td>
<td>0.8</td>
<td>30</td>
<td></td>
<td>nA</td>
</tr>
<tr>
<td></td>
<td>Measured at (V_{\text{IN}} = \pm V_{\text{RWM}}), (T_{\text{A}} = 27^\circ) C</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td>Measured at (V_{\text{IN}} = \pm V_{\text{RWM}}), (T_{\text{A}} = 85^\circ) C</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>V(_{\text{BR}})</td>
<td>Break-down Voltage</td>
<td>29.6</td>
<td>32</td>
<td>35.7</td>
<td>V</td>
</tr>
<tr>
<td>V(_{\text{CLAMP}})</td>
<td>Clamp Voltage (\pm I_{\text{PP}}) IEC 61000-4-5 Surge (8/20 (\mu)s), (V_{\text{IN}} = 0) V before surge, (T_{\text{A}} = 27^\circ) C</td>
<td>34</td>
<td></td>
<td>37.3</td>
<td>V</td>
</tr>
<tr>
<td></td>
<td>(\pm I_{\text{PP}}) IEC 61000-4-5 Surge (8/20 (\mu)s), (V_{\text{IN}} = \pm V_{\text{RWM}}) before surge, (T_{\text{A}} = 125^\circ) C</td>
<td>34.7</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>R(_{\text{DYN}})</td>
<td>8/20 (\mu)s surge dynamic resistance Calculated from (V_{\text{CLAMP}}) at (0.5 I_{\text{PP}}) and (I_{\text{PP}}) surge current, (T_{\text{A}} = 25^\circ) C</td>
<td>40</td>
<td></td>
<td></td>
<td>m(\Omega)</td>
</tr>
<tr>
<td>C(_{\text{IN}})</td>
<td>Input pin capacitance (V_{\text{IN}} = V_{\text{RWM}}, f = 1) MHz, 30 mV(\text{pp}), IO to GND</td>
<td>57</td>
<td></td>
<td></td>
<td>pF</td>
</tr>
<tr>
<td>SR</td>
<td>Maximum Slew Rate 0(-\pm V_{\text{RWM}}) rising edge, sweep rise time and measure slew rate when (I_{\text{PEAK}} = 1) mA, (T_{\text{A}} = 27^\circ) C</td>
<td>2.5</td>
<td></td>
<td></td>
<td>V/(\mu)s</td>
</tr>
<tr>
<td></td>
<td>0(-\pm V_{\text{RWM}}) rising edge, sweep rise time and measure slew rate when (I_{\text{PEAK}} = 1) mA, (T_{\text{A}} = 85^\circ) C</td>
<td>1.0</td>
<td></td>
<td></td>
<td>V/(\mu)s</td>
</tr>
</tbody>
</table>
7.7 Typical Characteristics

**Figure 1. 8/20 µs Surge Response at 27 A**

- Voltage (V) vs Current (A)
- Time (µs)

**Figure 2. 8/20 µs Surge Clamping Response at 27 A**

- Voltage (V)
- Temperature (°C)

**Figure 3. Capacitance vs Voltage Bias**

- Capacitance (pF)
- Voltage (V)
- f = 1 MHz, 30 mVpp, IO to GND

**Figure 4. Leakage Current vs Temperature at 27 V**

- Leakage (nA)
- Temperature (°C)

**Figure 5. Breakdown Voltage (1 mA) vs Temperature**

- Voltage (V)
- Temperature (°C)

**Figure 6. Dynamic Leakage vs Signal Slew Rate Across Temperature**

- Dynamic Leakage (mA)
- Slew Rate (V/µs)
- Temperature
8 Detailed Description

8.1 Overview

The TVS2701 is a bidirectional precision clamp with two integrated FETs driven by a feedback loop to tightly regulate the input voltage during an overvoltage event. This feedback loop leads to a very low dynamic resistance, giving a flat clamping voltage during transient overvoltage events like a surge.

8.2 Functional Block Diagram

![Functional Block Diagram of TVS2701]

8.3 Feature Description

The TVS2701 is a precision clamp that handles 27 A of IEC 61000-4-5 8/20-µs surge pulse. The flat clamping feature helps keep the clamping voltage very low to keep the downstream circuits from being stressed. The flat clamping feature can also help end-equipment designers save cost by opening up the possibility to use low-cost, lower voltage tolerant downstream ICs. This device provides a bidirectional operating range, with a symmetrical $V_{\text{RWM}}$ of ±27 V designed for applications that have bipolar input signals or that must withstand reverse wiring conditions. The TVS2701 has minimal leakage at $V_{\text{RWM}}$, designed for applications where low leakage and power dissipation is a necessity. Built-in IEC 61000-4-2 and IEC 61000-4-4 ratings make it a robust protection solution for ESD and EFT events and the TVS2701 wide ambient temperature range of –40°C to +125°C enables usage in harsh industrial environments.

8.4 Device Functional Modes

8.4.1 Protection Specifications

The TVS2701 is specified according to both the IEC 61000-4-5 and IEC 61643-321 standards. This enables usage in systems regardless of which standard is required by relevant product standards or best matches measured fault conditions. The IEC 61000-4-5 standard requires protection against a pulse with a rise time of 8 µs and a half-length of 20 µs, while the IEC 61643-321 standard requires protection against a much longer pulse with a rise time of 10 µs and a half-length of 1000 µs.
Device Functional Modes (continued)

The positive and negative surges are imposed to the TVS2701 by a combination wave generator (CWG) with a 2-Ω coupling resistor at different peak voltage levels. For powered-on transient tests that need power supply bias, inductances are used to decouple the transient stress and protect the power supply. The TVS2701 is post-tested by assuring that there is no shift in device breakdown or leakage at $V_{RWM}$.

In addition, the TVS2701 has been tested according to IEC 61000-4-5 to pass a ±1-kV surge test through a 42-Ω coupling resistor and a 0.5-µF capacitor. This test is a common test requirement for industrial signal I/O lines and the TVS2701 precision clamp can be used in applications that have that requirement.

The TVS2701 integrates IEC 61000-4-2 level 4 ESD Protection and 80 A of IEC 61000-4-4 EFT Protection. These combine to ensure that the device can protect against most common transient test requirements.

For more information on TI's test methods for Surge, ESD, and EFT testing, refer to the IEC 61000-4-x Tests for TI's Protection Devices application report.

8.4.2 Reliability Testing

To ensure device reliability, the TVS2701 is characterized against 5000 repetitive pulses of 25-A IEC 61000-4-5 8/20-µs surge pulses at 125°C. The test is performed with less than 10 seconds between each pulse at high temperature to simulate worst-case scenarios for fault regulation. After each surge pulse, the TVS2701 clamping voltage, breakdown voltage, and leakage are recorded to ensure that there is no variation or performance degradation. By ensuring robust, reliable, high temperature protection, the TVS2701 enables fault protection in applications that must withstand years of continuous operation with no performance change.

8.4.3 Zero Derating

Unlike traditional diodes, the TVS2701 has zero derating of maximum power dissipation and ensures robust performance up to 125°C. Traditional TVS diodes lose up to 50% of their current carrying capability when at high temperatures, so a surge pulse above 85°C ambient can cause failures that are not seen at room temperature. The TVS2701 prevents this so the designer can see the surge protection regardless of temperature. Because of this, Flat-Clamp devices can provide robust protection against surge pulses that occur at high ambient temperatures, as shown in TI's TVS Surge Protection in High-Temperature Environments application report.

8.4.4 Bidirectional Operation

The TVS2701 is a bidirectional TVS with a symmetrical operating region. This allows for operation with positive and negative voltages, rather than just positive voltages like the unidirectional TVS2700. This allows for single chip protection for applications where the signal is expected to operate below 0 V or where there is a need to withstand a large common-mode voltage. In addition, in many cases, there is a system requirement to be able to withstand reverse wiring conditions, in many cases where a high voltage signal is accidentally applied to the system ground and a ground is accidentally applied to the input terminal. This causes a large reverse voltage on the TVS diode that the device must be able to withstand. The TVS2701 is designed to not break down or see failures under reverse wiring conditions, for applications that must withstand these miswiring issues.

NOTE
If the applied signal is not expected to go below 0 V, a unidirectional device will clamp much lower in the reverse direction and should be used. In this case, the recommended device would be the TVS2700.

8.4.5 Transient Performance

During large transient swings, the TVS2701 will begin clamping the input signal to protect downstream conditions. While this prevents damage during fault conditions, it can cause leakage when the intended input signal has a fast slew rate. To keep power dissipation low and remove the chance of signal distortion, TI recommends that the designer keep the slew rate of any input signal on the TVS2701 below 2.5 V/µs at room temperature and below 1.0 V/µs at 85°C shown in Figure 6. Faster slew rates will cause the device to clamp the input signal and draw current through the device for a few microseconds, increasing the rise time of the signal. This will not cause any harm to the system or to the device, however if can cause device overheating if the fast input voltage swings occur regularly.
9 Application and Implementation

NOTE
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI’s customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information
The TVS2701 can be used to protect any power, analog, or digital signal from transient fault conditions caused by the environment or other electrical components. A common application will be protecting both the PLC and sensor transmitter in industrial applications, as shown. More detail will be given on the protection on the PLC side as the input signal is connected to the input of a multiplexer.

Figure 7. TVS2701 Application Example

9.2 Typical Application

Figure 8. TVS2700 Application Schematic
Typical Application (continued)

9.2.1 Design Requirements

A typical operation for the TVS2701 would be in a multi-channel PLC protecting an analog input, shown in Figure 8. In this example, a TVS2701 is protecting the input to a MUX36D04, a four channel input multiplexer with a supply maximum at 36 V. In addition, the application must be able to withstand reverse wiring conditions with no damage caused to the input circuitry. Without any input protection, this input voltage will rise to hundreds of volts for multiple microseconds and violate the absolute maximum input voltage and harm the device if a surge event is caused by lightning, coupling, ringing, or any other fault condition. TI’s Flat-Clamp technology provides surge protection diodes that can maximize the useable voltage range and clamp at a safe level for the system.

9.2.2 Detailed Design Procedure

If the TVS2701 is in place to protect the device, the voltage will rise to the breakdown of the diode at 32 V during a surge event. The TVS2701 will then turn on to shunt the surge current to ground. With the low dynamic resistance of the TVS2701, even large amounts of surge current will have minimal impact on the clamping voltage. The dynamic resistance of the TVS2701 is around 40 mΩ, which means a 25-A surge current will cause a voltage raise of 25 A × 40 mΩ = 1 V. Because the device turns on at 32 V, this means the module input will be exposed to a maximum of 32 V + 1 V = 33 V during surge pulses, well within the MUX36D04 absolute maximum.

In addition, because the TVS2701 is a bidirectional device it is designed to withstand reverse wiring conditions. When the supplies is wired backwards, it applies –27 V to the V_{INPUT} relative to ground, which does not break down the TVS diode, and does not damage the input to the MUX36D04 because of the reverse current protection diode. If a unidirectional diode like the TVS2700 were used in this case, the –27 V would cause the diode to shunt current until it overheat and breaks.

Finally, the small size of the device also improves fault protection by lowering the effect of fault current coupling onto neighboring traces. The small form factor of the TVS2701 allows the device to be placed extremely close to the input connector, which lowers the length of the path fault current going through the system compared to larger protection solutions.

9.2.3 Application Curves

When a surge is applied to the system with the TVS2701, the device will clamp the surge as shown in Figure 9.

![Figure 9. TVS2701 Surge Response at 27 A](image-url)
11 Layout

11.1 Layout Guidelines

The optimum placement is close to the connector. EMI during an ESD event can couple from the tested trace to other nearby unprotected traces, which could result in system failures. The PCB designer must minimize the possibility of EMI coupling by keeping all unprotected traces away from protected traces between the TVS and the connector. Route the protected traces straight. Use rounded corners with the largest radii possible to eliminate any sharp corners on the protected traces between the TVS2701 and the connector. Electric fields tend to build up on corners, which could increase EMI coupling.

Ensure that the thermal pad on the layout is floating rather than grounded. Grounding the thermal pad will impede the operating range of the TVS2701, and can cause failures when the applied voltage is negative. A floating thermal pad allows the maximum operating range without sacrificing any transient performance.

11.2 Layout Example

![TVS2701 Layout](image)

Figure 10. TVS2701 Layout
12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- Flat-Clamp Surge Protection Technology for Efficient System Protection
- IEC 61000-4-x Tests for TI’s Protection Devices
- TVS Surge Protection in High-Temperature Environments

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Community Resources

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**Design Support**  *TI’s Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

E2E is a trademark of Texas Instruments.

12.5 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

**SLYZ022 — TI Glossary.**

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.
<table>
<thead>
<tr>
<th>Orderable Device</th>
<th>Status (1)</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>PIns</th>
<th>Package Qty</th>
<th>Eco Plan (2)</th>
<th>Lead/Ball Finish (6)</th>
<th>MSL Peak Temp (3)</th>
<th>Op Temp (°C)</th>
<th>Device Marking (4/5)</th>
<th>Samples</th>
</tr>
</thead>
<tbody>
<tr>
<td>TVS2701DRBR</td>
<td>ACTIVE</td>
<td>SON</td>
<td>DRB</td>
<td>8</td>
<td>3000</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>CU NIPDAU</td>
<td>Level-2-260C-1 YEAR</td>
<td>-40 to 125</td>
<td>1PTP</td>
<td></td>
</tr>
</tbody>
</table>

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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## TAPE AND REEL INFORMATION

### REEL DIMENSIONS

- **Reel Diameter**
- **Reel Width (W1)**

### TAPE DIMENSIONS

- **K0** Dimension designed to accommodate the component width
- **B0** Dimension designed to accommodate the component length
- **W** Overall width of the carrier tape
- **P1** Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

- **Q1**
- **Q2**
- **Q3**
- **Q4**

*All dimensions are nominal.*

<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Reel Diameter (mm)</th>
<th>Reel Width W1 (mm)</th>
<th>A0 (mm)</th>
<th>B0 (mm)</th>
<th>K0 (mm)</th>
<th>P1 (mm)</th>
<th>W (mm)</th>
<th>Pin 1 Quadrant</th>
</tr>
</thead>
<tbody>
<tr>
<td>TVS2701DRBR</td>
<td>SON</td>
<td>DRB</td>
<td>8</td>
<td>3000</td>
<td>330.0</td>
<td>12.4</td>
<td>3.3</td>
<td>3.3</td>
<td>1.1</td>
<td>8.0</td>
<td>12.0</td>
<td>Q2</td>
</tr>
</tbody>
</table>
TAPE AND REEL BOX DIMENSIONS

*All dimensions are nominal

<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Length (mm)</th>
<th>Width (mm)</th>
<th>Height (mm)</th>
</tr>
</thead>
<tbody>
<tr>
<td>TVS2701DRBR</td>
<td>SON</td>
<td>DRB</td>
<td>8</td>
<td>3000</td>
<td>338.0</td>
<td>355.0</td>
<td>50.0</td>
</tr>
</tbody>
</table>
Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.
NOTES:
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.
NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
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